Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,631	LEE, CHUNG KEE
Examiner	Art Unit
Frederick C. Nicolas	3754

SEARCHED						
Class	Subclass	Date	Examiner			
222	212,494, 490, 325,328, 335,531	2/7/2005	NK			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

DATE	EXMR
2/16/2006	FN
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